CEMENT AND CONCRETE REFERENCE LABORATORY PROFICIENCY SAMPLE PROGRAM

Final Report
Pozzolan Proficiency Samples
Number 33 and Number 34

October 2003



CEMENT AND CONCRETE REFERENCE LABORATORY

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COMMITTEE C-9 ON CONCRETE AND
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AMERICAN SOCIETY FOR TESTING AND MATERIALS

October 24, 2003

To: Participants in the CCRL Pozzolan Proficiency Sample Program

SUBJECT: Pozzolan Proficiency Samples No. 33 and No. 34

Enclosed is your copy of the final report on the test results for the CCRL **Pozzolan** Proficiency Samples which were distributed in August 2003.

This report consists of a Table of Results for individual laboratory data, a statistical Summary of Results, a set of general Scatter Diagrams and associated detailed information.

The CCRL Proficiency Sample Programs are intended for internal use by the laboratory as a tool to identify potential problems in laboratory procedures or test equipment and to initiate remedial actions. These programs are designed to complement the CCRL Laboratory Inspection Program as part of a total quality system. Care should be taken when using this program for any other use.

It is presently anticipated that the next Pozzolan Proficiency Samples will be distributed in August 2004.

Sincerely,

Robin K. Haupt

Supervisor, Proficiency Sample Programs Cement and Concrete Reference Laboratory Materials and Construction Research Division Building and Fire Research Laboratory

Rolm K. Hauget

Enclosure

To: Participants in the CCRL Pozzolan Proficiency Sample Program

FROM: Robin K. Haupt, Supervisor, PSP

SUBJECT: Explanation of Final Report on Results of Tests on Pozzolan Proficiency Samples No. 33 and No. 34

This letter, and the material included with it, constitute the final report and summary of results for the current pair of Pozzolan Proficiency Samples, which were distributed in August 2003. This material includes a Table of Results for individual laboratory data, a statistical Summary of Results, and a set of general Scatter Diagrams. Your unique laboratory number is displayed at the top of the individual Table of Results.

An explanation of the program is contained in the paper: "Statistical Evaluation of Interlaboratory Cement Tests" by J. R. Crandall and R. L. Blaine, and "Statistical Aspects of the Cement Testing Program" by W.J. Youden, which can be found in Volume 59, Proceedings of the 62nd Annual Meeting of the Society, June 25, 1959, American Society for Testing and Materials.

Laboratory Ratings

Each laboratory receives an individualized Laboratory Ratings. Each line of the ratings shows the test number, test title and the reporting unit in the first three columns. After that it lists in order the laboratory's results for the odd and even numbered samples, overall averages for the odd and even numbered samples, and the laboratory's ratings for the odd and even samples.

The ratings for the individual laboratory were determined in the manner described by Crandall and Blaine using a rating scale 1 to 5 instead of 0 to 4. The ratings have no valid standing beyond showing the difference between the individual laboratory result and the average for a particular test.

The following table details the relationship between the ratings and the averages.

Ratings	Range (Number of Standard Deviations)	Number (Per 100) of Laboratories achieving the rating ¹		
5	Less than 1	69		
4	1 to 1.5	18		
3	1.5 to 2	9		
2	2 to 2.5	3		
1	Greater than 2.5	1		

The sign of the rating merely shows whether the result reported was greater or less than the average obtained.

¹Youden, W.J., "Statistical Aspects of the Cement Testing Program", Volume 59, *Proceedings of the 62nd Annual Meeting of the Society, June 25, 1959, American Society for Testing and Materials.*

In cases where some laboratories' results are eliminated, averages, standard deviations, coefficients of variation and the ratings of the other laboratories' results, are recalculated using the data remaining after the elimination. Since the laboratory ratings given are the results from this one series of tests, you need not attach too much significance to a single low rating, or pair of ratings, from this one series. A continuing tendency to get low ratings on several pairs of samples should lead a laboratory to consider the types of error, systematic and random, which contribute to ratings that are low. Systematic error, which is indicated by low ratings with the same signs on each pair of samples, means a consistent error is occurring in equipment and/or test procedures. One indication of random error is low ratings on both samples with different signs. Since systematic error occurs with more regularity, its cause is generally easier to find than the cause of random error.

Summary of Results

Usually, averages, standard deviations, and coefficients of variation are given with all results reported, and then with one or more outlying results omitted. Sometimes, two or more recalculations with laboratories omitted, have been done for the same test. In these cases, all of the laboratories omitted in previous recalculations are also omitted in subsequent ones. Results omitted are values that are more than three standard deviations from the mean of one or both samples. Often, elimination of these outlying results has little effect on the average, but may have a more pronounced effect on the standard deviation and coefficient of variation.

Scatter Diagrams

General scatter diagrams are supplied with this report. Crandall and Blaine describe the manner of preparing scatter diagrams, and their interpretation, in the paper published in the 1959 ASTM Proceedings. Each laboratory will receive a complete set of diagrams according to their participation in chemical and/or physical tests.

Using the results received from each laboratory, a scatter diagram is generated for each test method by plotting the value for the odd numbered samples on the X, or horizontal axis, against the value for the even numbered samples on the Y, or vertical axis. To find your point, just plot as you would when plotting any scatter diagram. Vertical and horizontal dashed lines, which divide the diagrams into four sections or quadrants, place the average values for the odd and even numbered samples, respectively. The first line of print under the diagram includes the test number, as given on the data sheet, the test title, and the number of data points on the diagrams. The number of plotted points may not agree with the total number of data pairs included in the analysis because a few points may be off the diagram, and some points may represent several data pairs, which are identical. Laboratories whose points are off the diagram will have a rating of ± 1 for that particular test.

As described in Crandall and Blaine, a tight circular pattern of points around the intersection of the median lines is the ideal situation. Stretching out of the pattern into the first (upper right) and third (lower left) quadrants, suggests some kind of bias, or tendency for laboratories to get high or low results on both samples. Examination of the scatter diagrams may indicate strong evidence of bias in many cases.

CCRL PROFICIENCY SAMPLE PROGRAM

Pozzolan Proficiency Samples No. 33 and No. 34 Final Report - Chemical Results October 24, 2003

SUMMARY OF RESULTS

Sample No. 33

Sample No. 34

Test		#L	abs	Average	S.D.	C.V.	Average	S.D.	C.V.
Moisture Content	prent		58	0.17	0.39	231	0.18	0.39	215
Moisture Content		*	55	0.11	0.072	65.6	0.12	0.075	62.0
Silicon Dioxide	prent		47	39.17	4.2	10.71	34.03	2.5	7.47
Silicon Dioxide	prent	*	44	40.12	1.1	2.65	34.61	1.1	3.15
Al ₂ O ₃ w/minor ¹	prent		25	20.68	6.4	30.8	21.25	4.5	21.1
Al_2O_3 w/minor ¹ $(P_2O_3 \& TiO_2)$ ir	prent	*	22	20.06	1.1	5.38	21.79	1.4	6.23
$(P_2O_3 \times 11O_2)$	iciudea,)							
Al ₂ O ₃ wo/minor ²			37	18.08	4.8	26.5	18.82	3.4	18.0
Al ₂ O ₃ wo/minor ²		*	35	17.93	1.0	5.67	19.09	1.0	5.44
² (P ₂ O ₃ & TiO ₂ not included)									
Ferric Oxide	prent		46	6.45	0.78	12.0	5.94	0.69	11.7
Ferric Oxide	prent	*	44	6.45	0.51	7.95	5.96	0.46	7.79
Calcium Oxide	prent		49	22.46	1.3	5.77	25.29	1.3	5.05
CONTINUED ON REVERSE SIDE									

* ELIMINATED LABS: Data over three S.D. from the mean

Moisture Content 25 29 176
Silicon Dioxide 3 41 2150
Al Oxide w/minor oxides 207 176 2150
Al Oxide wo/minor oxides 207 2150
Ferric Oxide 3 158

CCRL PROFICIENCY SAMPLE PROGRAM

Pozzolan Proficiency Samples No. 33 and No. 34 Final Report - Chemical Results October 24, 2003

SUMMARY OF RESULTS

Sample No. 33

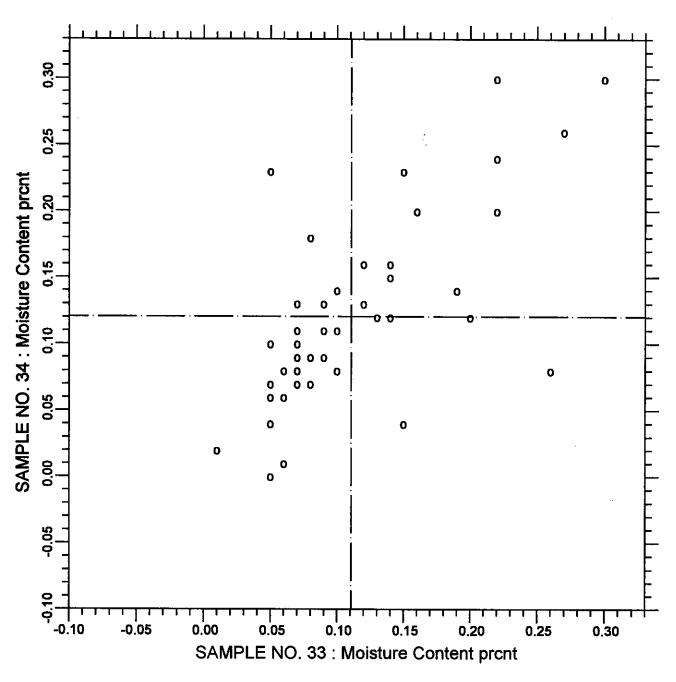
Sample No. 34

Test		#I	Labs	Average	S.D.	C.V.	Average	S.D.	C.V.
Magnesium Oxide	e prent		48	4.73	0.74	15.7	5.73	0.88	15.4
Magnesium Oxide prent		*	46	4.86	0.39	8.03	5.89	0.43	7.25
Sulfur Trioxide	prent		54	1.71	0.17	9.98	1.65	0.20	12.20
Sulfur Trioxide	prent	*	52	1.69	0.13	7.92	1.63	0.16	10.11
Loss on Ignition	prent		62	0.57	0.12	20.1	0.38	0.15	40.3
Loss on Ignition	prent	*	60	0.57	0.12	20.4	0.36	0.11	29.5
Sodium Oxide	prent		43	1.30	0.28	21.9	1.77	0.35	19.7
Potassium Oxide	prent		42	0.63	0.059	9.48	0.48	0.060	12.53
Potassium Oxide	prent	*	41	0.63	0.044	6.94	0.49	0.043	8.83
Available Na ₂ O	prent		21	1.02	0.47	46.3	1.34	0.51	37.8
Available Na ₂ O	prent	*	20	0.92	0.15	16.6	1.24	0.19	15.6
Available K ₂ O	prent		21	0.36	0.118	32.8	0.31	0.096	31.4
Available K ₂ O	prent	*	20	0.34	0.068	20.0	0.29	0.054	18.5
Available Alkali	prent		21	1.26	0.55	43.4	1.54	0.57	36.8
Available Alkali	prent	*	20	1.15	0.19	16.8	1.43	0.22	15.8

* ELIMINATED LABS: Data over three S.D. from the mean

Magnesium Oxide 47 2116
Sulfur Trioxide 38 44
Loss on Ignition 29 205
Potassium Oxide 176
Available Sodium Oxide 15
Available Potassium Oxide 15
Available Alkali 15

CCRL PROFICIENCY SAMPLE PROGRAM Moisture Content POZZOLAN SAMPLES NO. 33 & NO. 34



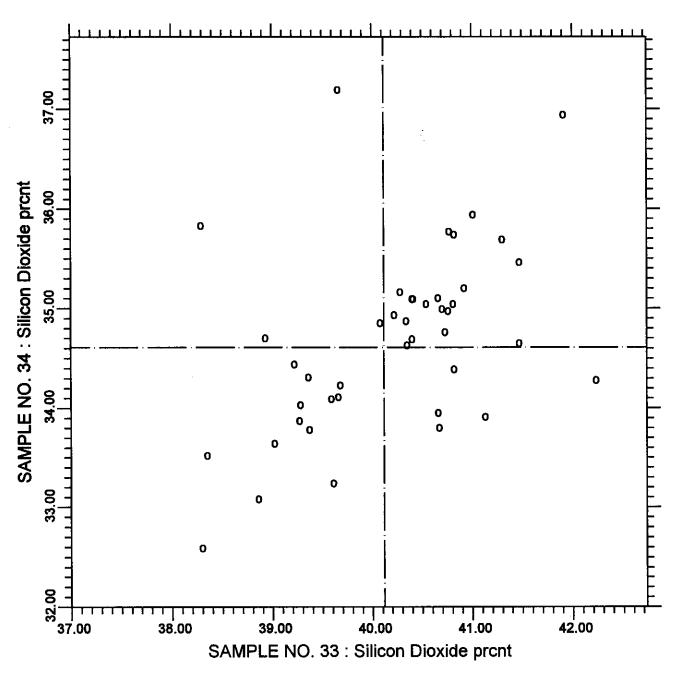
TEST NO.5

Moisture Content

54 POINTS

SAMPLE NO. 33 AVE 0.1105 S.D. 0.072 C.V. 65.6 SAMPLE NO. 34 AVE 0.1204 S.D. 0.075 C.V. 62.0 LABS ELIMINATED 25 29 176 LABS OFF DIAGRAM 41

CCRL PROFICIENCY SAMPLE PROGRAM Silicon Dioxide POZZOLAN SAMPLES NO. 33 & NO. 34



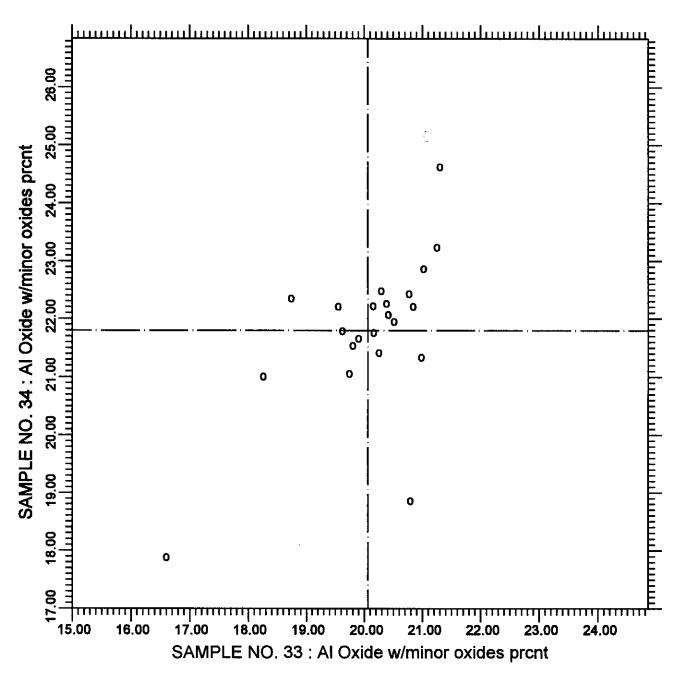
TEST NO.10

Silicon Dioxide

43 POINTS

SAMPLE NO. 33 AVE 40.12 S.D. 1.1 C.V. 2.65 SAMPLE NO. 34 AVE 34.61 S.D. 1.1 C.V. 3.15 LABS ELIMINATED 3 41 2150 LABS OFF DIAGRAM 44

CCRL PROFICIENCY SAMPLE PROGRAM Aluminum Oxide (minor oxides included) POZZOLAN SAMPLES NO. 33 & NO. 34



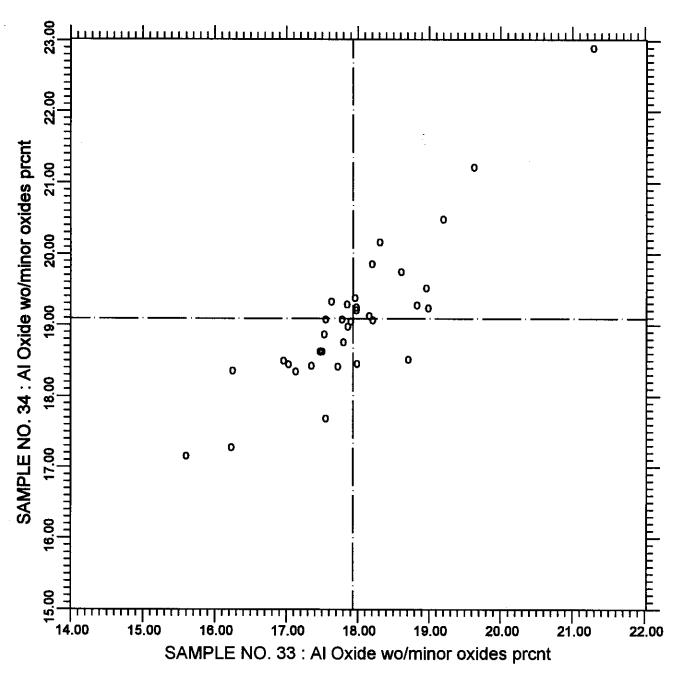
TEST NO.20

Al Oxide w/minor oxides

22 POINTS

SAMPLE NO. 33 AVE 20.06 S.D. 1.1 C.V. 5.38 SAMPLE NO. 34 AVE 21.79 S.D. 1.4 C.V. 6.23 LABS ELIMINATED 207 176 2150

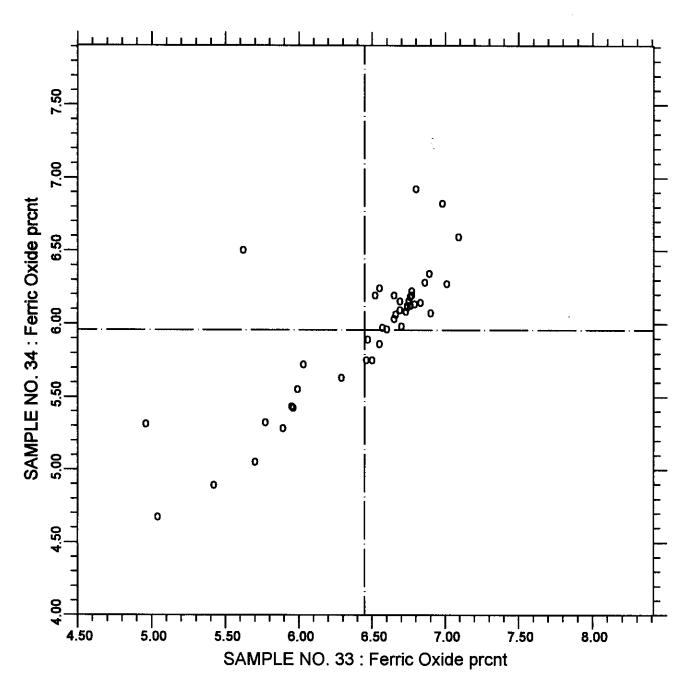
CCRL PROFICIENCY SAMPLE PROGRAM Aluminum Oxide (minor oxides excluded) POZZOLAN SAMPLES NO. 33 & NO. 34



TEST NO.21 Al Oxide wo/minor oxides 35 POINTS

SAMPLE NO. 33 AVE 17.93 S.D. 1.0 C.V. 5.67 SAMPLE NO. 34 AVE 19.09 S.D. 1.0 C.V. 5.44 LABS ELIMINATED 207 2150

CCRL PROFICIENCY SAMPLE PROGRAM Ferric Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



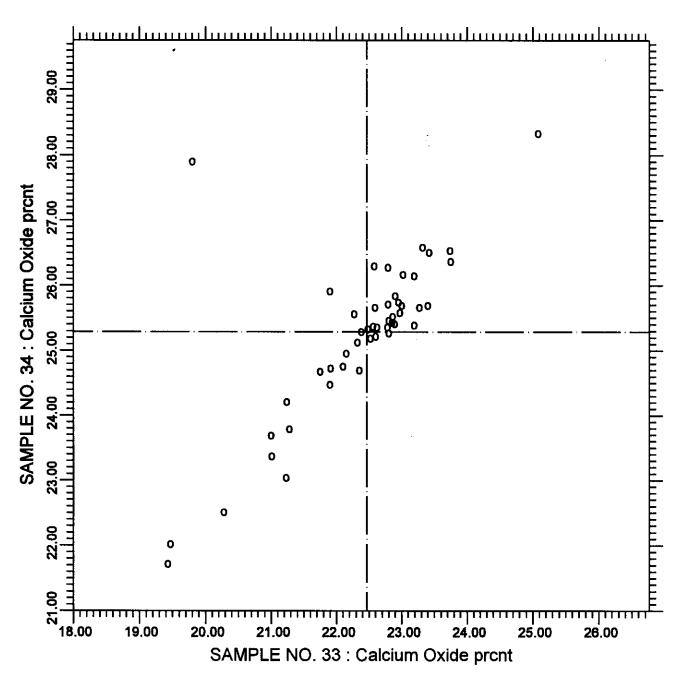
TEST NO.30

Ferric Oxide

44 POINTS

SAMPLE NO. 33 AVE 6.449 S.D. 0.51 C.V. 7.95 SAMPLE NO. 34 AVE 5.958 S.D. 0.46 C.V. 7.79 LABS ELIMINATED 3 158

CCRL PROFICIENCY SAMPLE PROGRAM Calcium Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



TEST NO.40

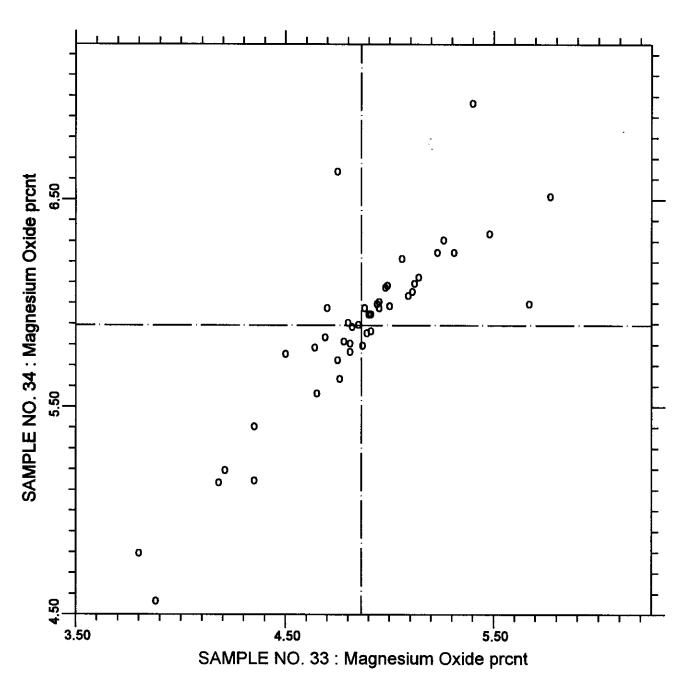
Calcium Oxide

48 POINTS

SAMPLE NO. 33 AVE 22.46 S.D. 1.3 C.V. 5.77 SAMPLE NO. 34 AVE 25.29 S.D. 1.3 C.V. 5.05

LABS OFF DIAGRAM 176

CCRL PROFICIENCY SAMPLE PROGRAM Magnesium Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



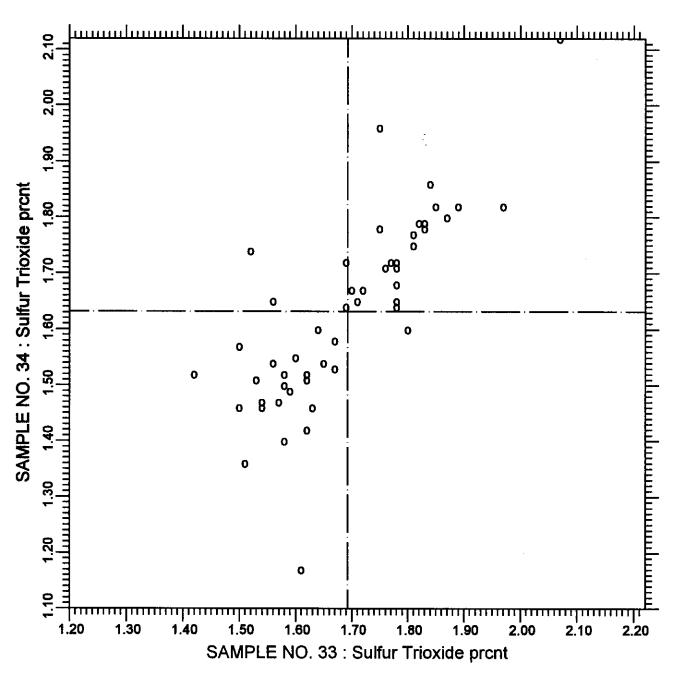
TEST NO.50

Magnesium Oxide

46 POINTS

SAMPLE NO. 33 AVE 4.865 S.D. 0.39 C.V. 8.03 SAMPLE NO. 34 AVE 5.893 S.D. 0.43 C.V. 7.25 LABS ELIMINATED 47 2116

CCRL PROFICIENCY SAMPLE PROGRAM Sulfur Trioxide POZZOLAN SAMPLES NO. 33 & NO. 34



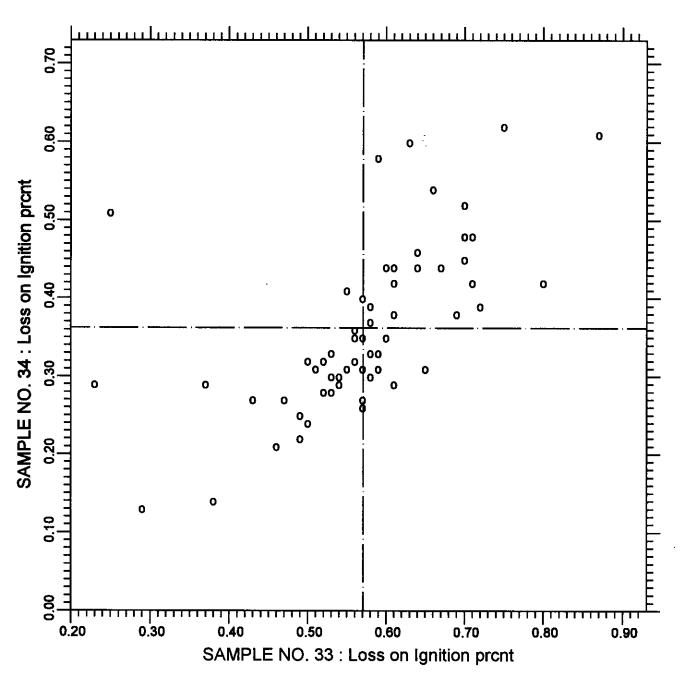
TEST NO.60

Sulfur Trioxide

52 POINTS

SAMPLE NO. 33 AVE 1.693 S.D. 0.13 C.V. 7.92 SAMPLE NO. 34 AVE 1.631 S.D. 0.16 C.V. 10.11 LABS ELIMINATED 38 44

CCRL PROFICIENCY SAMPLE PROGRAM Loss on Ignition POZZOLAN SAMPLES NO. 33 & NO. 34



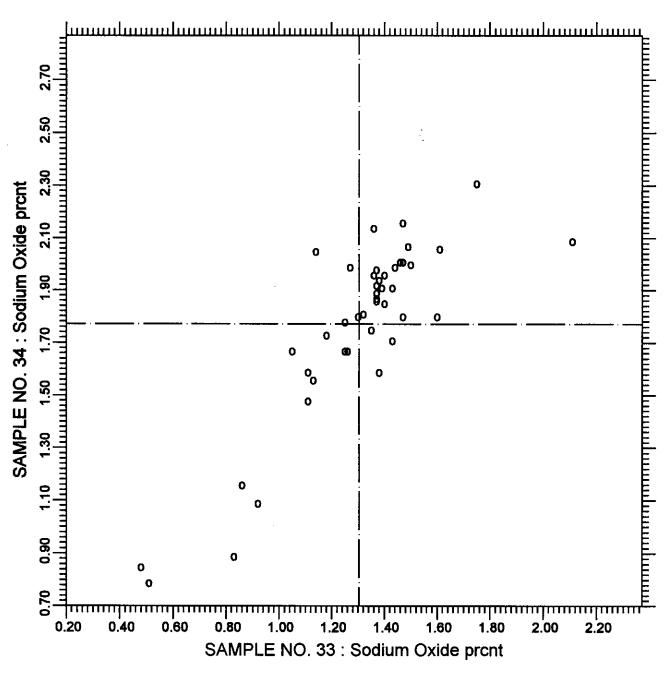
TEST NO.70

Loss on Ignition

60 POINTS

SAMPLE NO. 33 AVE 0.571 S.D. 0.12 C.V. 20.4 SAMPLE NO. 34 AVE 0.362 S.D. 0.11 C.V. 29.5 LABS ELIMINATED 29 205

CCRL PROFICIENCY SAMPLE PROGRAM Sodium Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



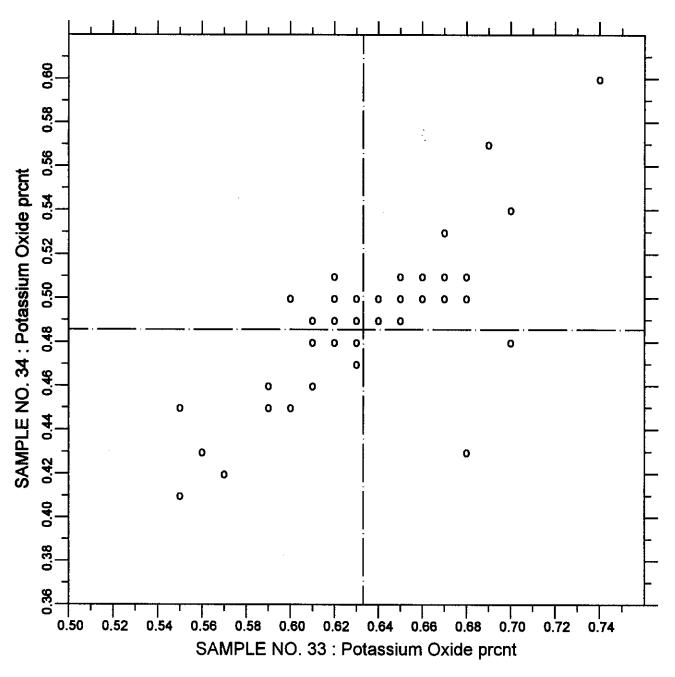
TEST NO.90

Sodium Oxide

43 POINTS

SAMPLE NO. 33 AVE 1.304 S.D. 0.28 C.V. 21.9 SAMPLE NO. 34 AVE 1.770 S.D. 0.35 C.V. 19.7

CCRL PROFICIENCY SAMPLE PROGRAM Potassium Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



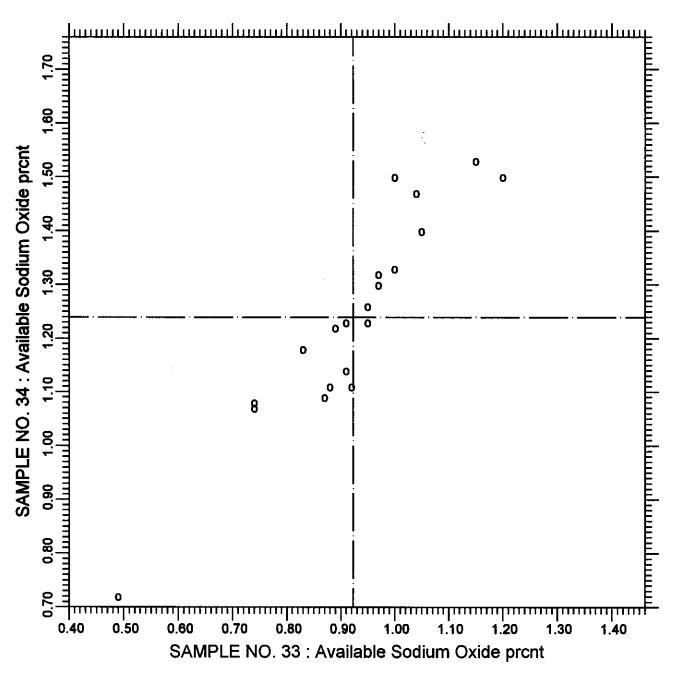
TEST NO.100

Potassium Oxide

40 POINTS

SAMPLE NO. 33 AVE 0.6332 S.D. 0.044 C.V. 6.94 SAMPLE NO. 34 AVE 0.4856 S.D. 0.043 C.V. 8.83 LABS ELIMINATED 176 LABS OFF DIAGRAM 44

CCRL PROFICIENCY SAMPLE PROGRAM Available Sodium Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



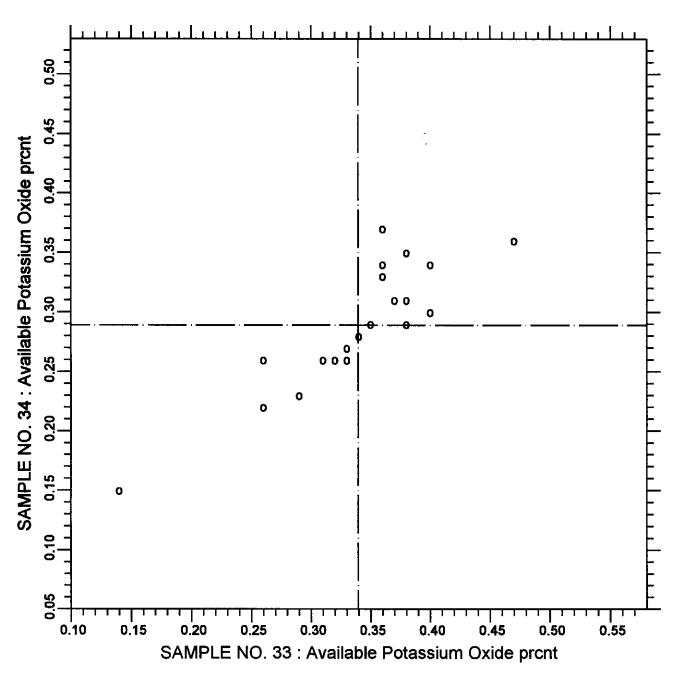
TEST NO.91 Available Sodium Oxide 20 POINTS

SAMPLE NO. 33 AVE 0.923 S.D. 0.15 C.V. 16.6

SAMPLE NO. 34 AVE 1.240 S.D. 0.19 C.V. 15.6

LABS ELIMINATED 15

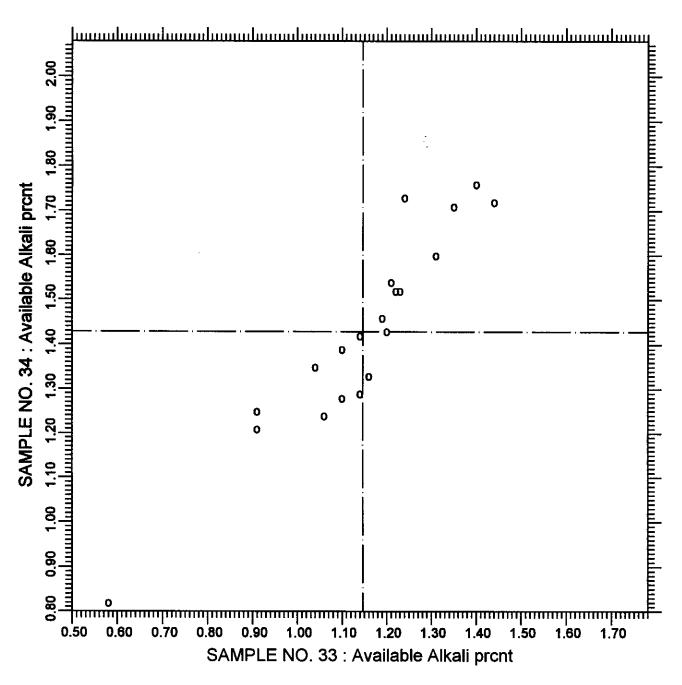
CCRL PROFICIENCY SAMPLE PROGRAM Available Potassium Oxide POZZOLAN SAMPLES NO. 33 & NO. 34



TEST NO.93 Available Potassium Oxide 20 POINTS

SAMPLE NO. 33 AVE 0.340 S.D. 0.068 C.V. 20.0 SAMPLE NO. 34 AVE 0.289 S.D. 0.054 C.V. 18.5 LABS ELIMINATED 15

CCRL PROFICIENCY SAMPLE PROGRAM Available Alkali POZZOLAN SAMPLES NO. 33 & NO. 34



TEST NO.95

Available Alkali

20 POINTS

SAMPLE NO. 33 AVE 1.146 S.D. 0.19 C.V. 16.8 SAMPLE NO. 34 AVE 1.428 S.D. 0.22 C.V. 15.8 LABS ELIMINATED 15

CCRL PROFICIENCY SAMPLE PROGRAM

Pozzolan Proficency Sample No. 33 and No. 34 Final Report - Physical Results October 24, 2003

SUMMARY OF RESULTS

Sample No. 33

Sample No. 34

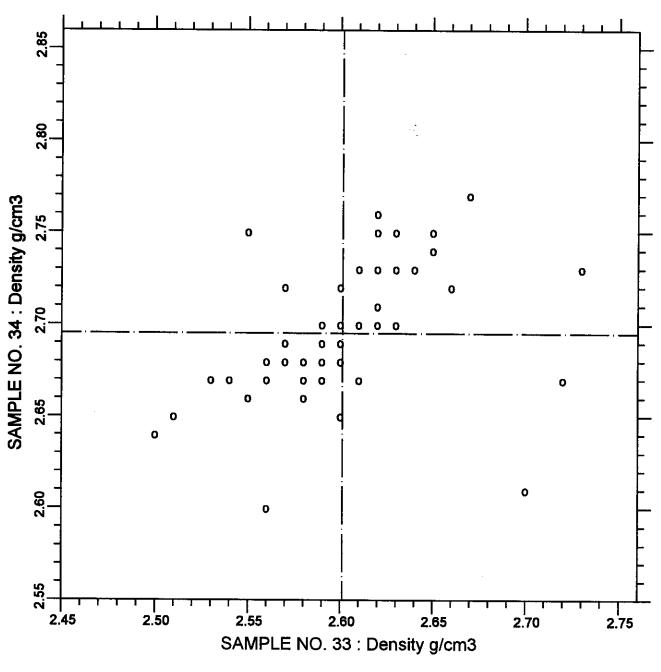
Test		#L	abs	Average	S.D.	C.V.	Average	S.D.	C.V.
Density	g/cm ³		57	2.59	0.058	2.22	2.69	0.046	1.71
Density	g/cm ³	*	53	2.60	0.044	1.71	2.70	0.035	1.31
45µm Sieve	prent		63	15.52	2.4	15.7	13.38	2.0	15.3
45µm Sieve	prent	*	62	15.77	1.4	9.20	13.59	1.2	8.50
D 01 ' 1			10	0.000	0.044	502	0.000	0.202	205
Dry Shrink	prent		12	0.008	0.044	592	0.099	0.283	285
Dry Shrink	prent	*	11	0.011	0.045	411	0.020	0.066	336
A . 1 F			47	0.12	0.040	22.1	0.12	0.040	20.0
Autoclave Expan	prent		47	0.12	0.040	33.1	0.13	0.040	30.9
N.C. Water	prent		47	24.6	1.01	4.12	24.2	0.92	3.82
N.C. Water	prent	*	46	24.4	0.33	1.35	24.1	0.32	1.35
N.C. Water	prent		40	24.4	0.55	1.55	24.1	0.32	1.55
Air Entrainment	prent		9	0.047	0.054	115	0.050	0.056	112
2111 2111111111111111111111111111111111	Promo			0.0.7	0.00	110	0.020	0.000	
STRENGTH ACTIV	VITY IN	DEX	(SA	I) WITH POR	TLAND CEN	MENT			
SAI 7 day	prent		51	93	4.6	4.92	95	5.0	5.34
	_								
SAI 28 day	prent		44	102	6.2	6.10	104	5.6	5.32
SAI Water	prent		49	96	1.8	1.94	95	1.9	2.04
The second of Marine and Assert Commence of the Commence of th									
EFFECTIVENESS OF MINERAL ADMIXTURES IN CONTROLLING ALKALI-SILICA REACTIONS (ASR)									
Reduction Expan	prent		6	28	11.2	40.8	20	7.8	39.2

Density 12 22 58 1882

45μm Sieve 158 Drying Shrinkage 205 N.C. Water 1773

^{*} ELIMINATED LABS: Data over three S.D. from the mean

CCRL PROFICIENCY SAMPLE PROGRAM Density POZZOLAN SAMPLES NO. 33 & NO. 34



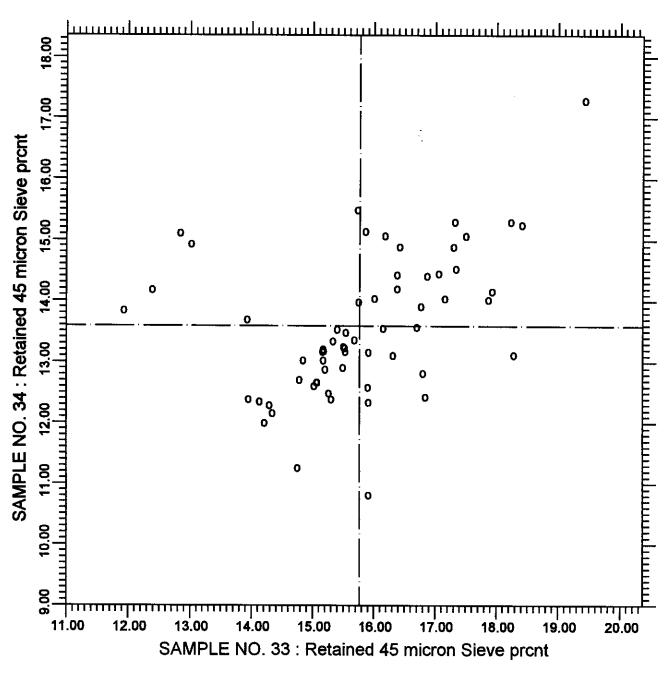
TEST NO.310

Density

53 POINTS

SAMPLE NO. 33 AVE 2.6011 S.D. 0.044 C.V. 1.71 SAMPLE NO. 34 AVE 2.6953 S.D. 0.035 C.V. 1.31 LABS ELIMINATED 12 22 58 1882

CCRL PROFICIENCY SAMPLE PROGRAM Fineness - 45 micron Sieve Retained POZZOLAN SAMPLES NO. 33 & NO. 34



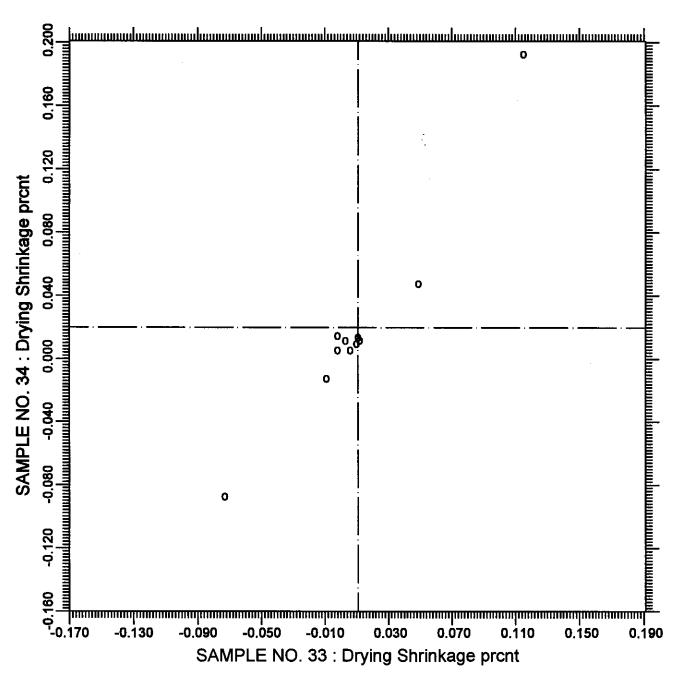
TEST NO.281

Retained 45 micron Sieve

62 POINTS

SAMPLE NO. 33 AVE 15.77 S.D. 1.4 C.V. 9.20 SAMPLE NO. 34 AVE 13.59 S.D. 1.2 C.V. 8.50 LABS ELIMINATED 158

CCRL PROFICIENCY SAMPLE PROGRAM Drying Shrinkage POZZOLAN SAMPLES NO. 33 & NO. 34



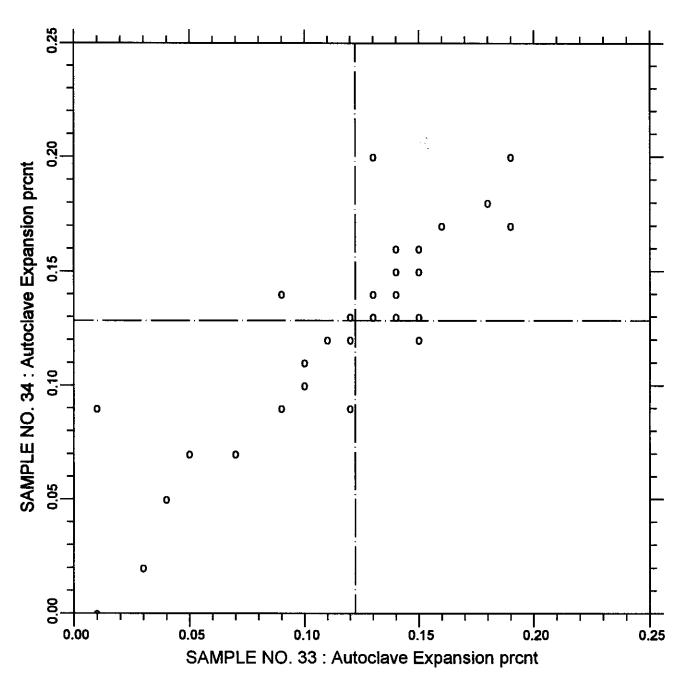
TEST NO.340

Drying Shrinkage

11 POINTS

SAMPLE NO. 33 AVE 0.011 S.D. 0.045 C.V. 411 SAMPLE NO. 34 AVE 0.020 S.D. 0.066 C.V. 336 LABS ELIMINATED 205

CCRL PROFICIENCY SAMPLE PROGRAM Autoclave Expansion POZZOLAN SAMPLES NO. 33 & NO. 34



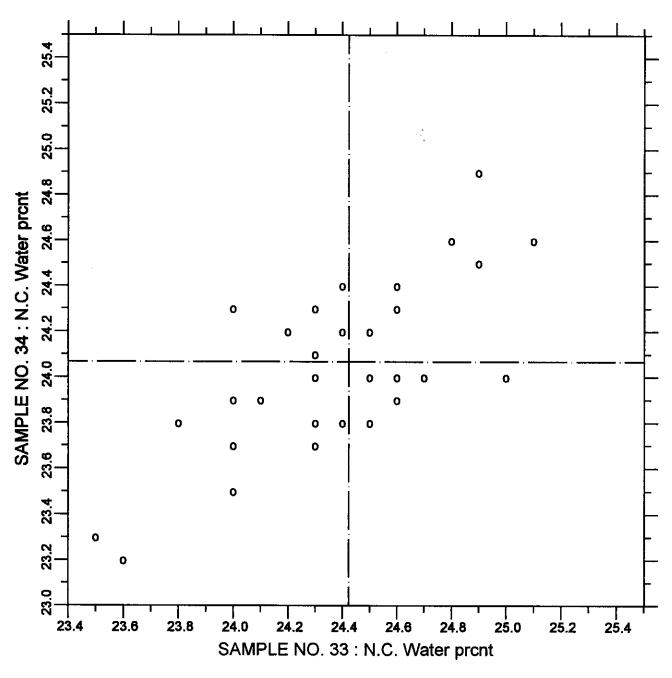
TEST NO.160

Autoclave Expansion

47 POINTS

SAMPLE NO. 33 AVE 0.1221 S.D. 0.040 C.V. 33.1 SAMPLE NO. 34 AVE 0.1283 S.D. 0.040 C.V. 30.9

CCRL PROFICIENCY SAMPLE PROGRAM Normal Consistency Water POZZOLAN SAMPLES NO. 33 & NO. 34



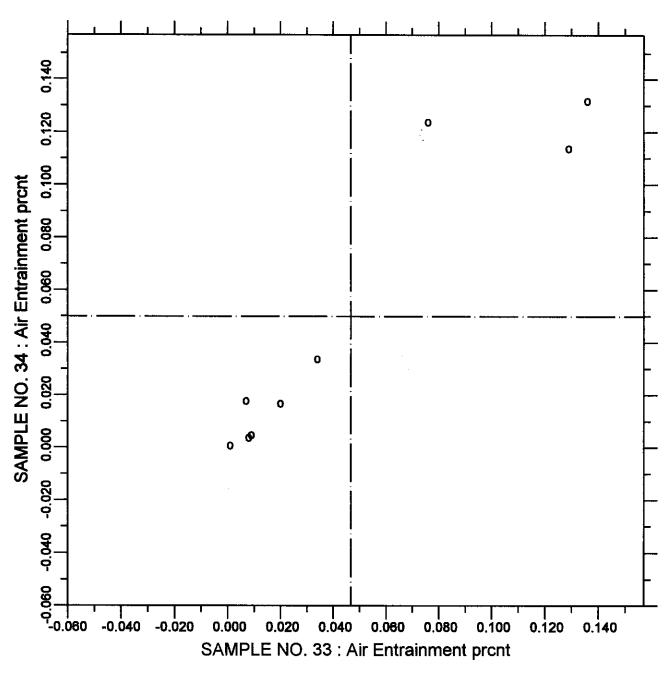
TEST NO.110

N.C. Water

46 POINTS

SAMPLE NO. 33 AVE 24.424 S.D. 0.33 C.V. 1.35 SAMPLE NO. 34 AVE 24.067 S.D. 0.32 C.V. 1.35 LABS ELIMINATED 1773

CCRL PROFICIENCY SAMPLE PROGRAM Air Entrainment POZZOLAN SAMPLES NO. 33 & NO. 34



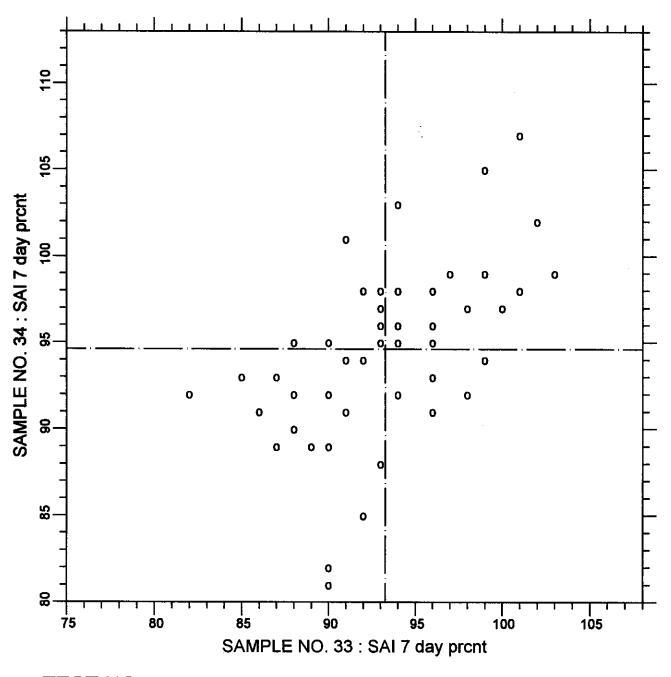
TEST NO.350

Air Entrainment

9 POINTS

SAMPLE NO. 33 AVE 0.047 S.D. 0.054 C.V. 115 SAMPLE NO. 34 AVE 0.050 S.D. 0.056 C.V. 112

CCRL PROFICIENCY SAMPLE PROGRAM Strength Activity Index - 7 day POZZOLAN SAMPLES NO. 33 & NO. 34



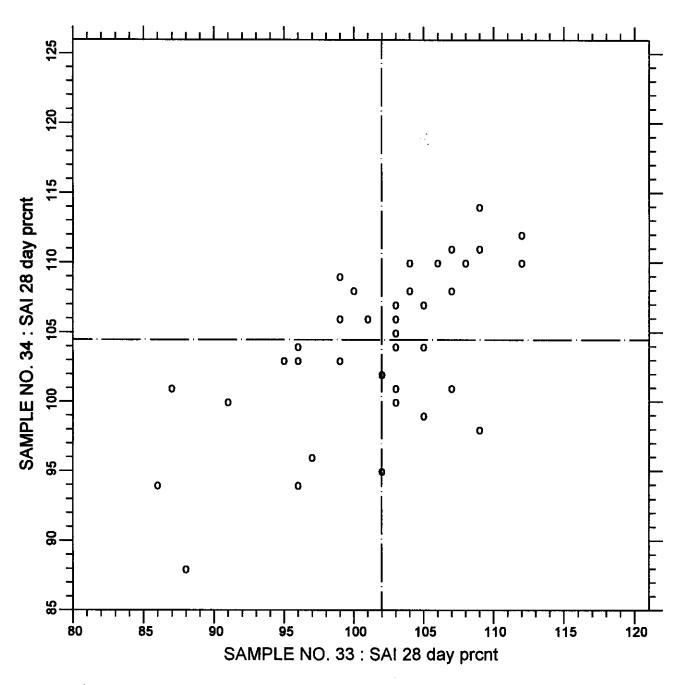
TEST NO.359

SAI 7 day

51 POINTS

SAMPLE NO. 33 AVE 93.27 S.D. 4.6 C.V. 4.92 SAMPLE NO. 34 AVE 94.61 S.D. 5.0 C.V. 5.34

CCRL PROFICIENCY SAMPLE PROGRAM Strength Activity Index - 28 day POZZOLAN SAMPLES NO. 33 & NO. 34



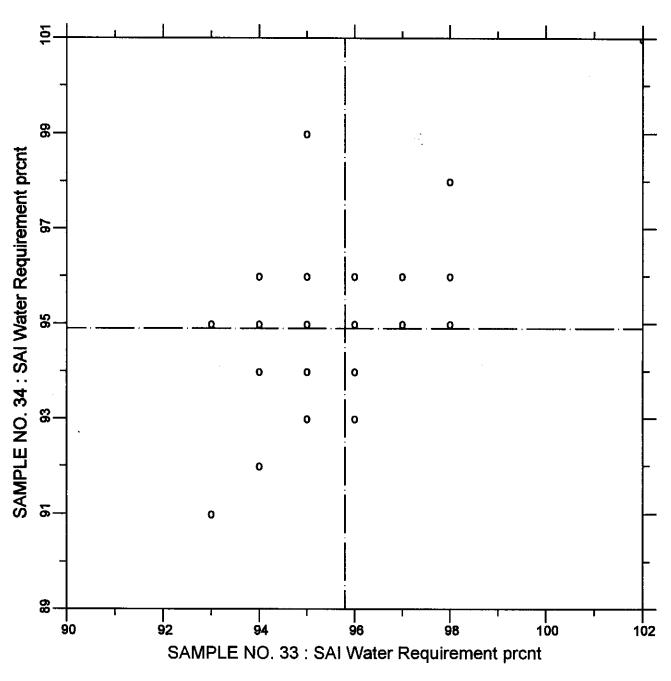
TEST NO.360

SAI 28 day

44 POINTS

SAMPLE NO. 33 AVE 101.98 S.D. 6.2 C.V. 6.10 SAMPLE NO. 34 AVE 104.48 S.D. 5.6 C.V. 5.32

CCRL PROFICIENCY SAMPLE PROGRAM SAI Water Requirement POZZOLAN SAMPLES NO. 33 & NO. 34



TEST NO.370

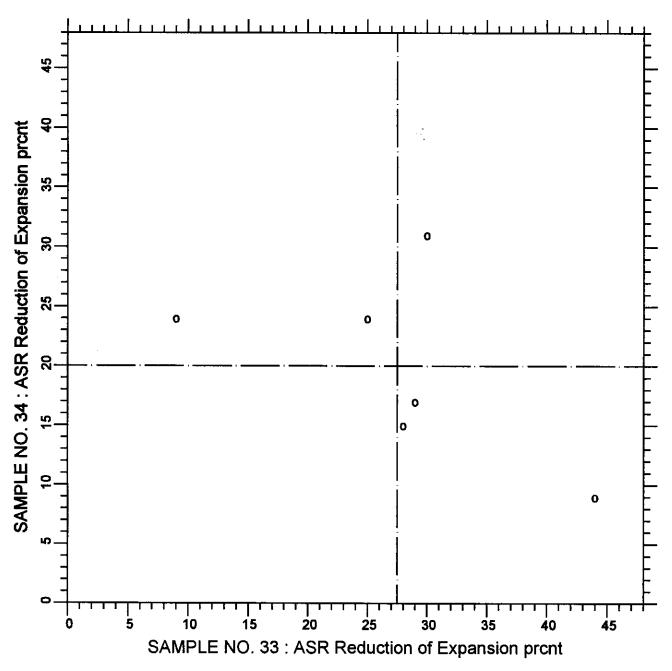
SAI Water Requirement

48 POINTS

SAMPLE NO. 33 AVE 95.80 S.D. 1.8 C.V. 1.94 SAMPLE NO. 34 AVE 94.90 S.D. 1.9 C.V. 2.04

LABS OFF DIAGRAM 207

CCRL PROFICIENCY SAMPLE PROGRAM Alkali-Silica Reaction - Reduction of Expansion POZZOLAN SAMPLES NO. 33 & NO. 34



TEST NO.390 ASR Reduction of Expansion 6 POINTS

SAMPLE NO. 33 AVE 27.5 S.D. 11.2 C.V. 40.8 SAMPLE NO. 34 AVE 20.0 S.D. 7.8 C.V. 39.2